



## N-CHANNEL POWER MOSFET MEM2504

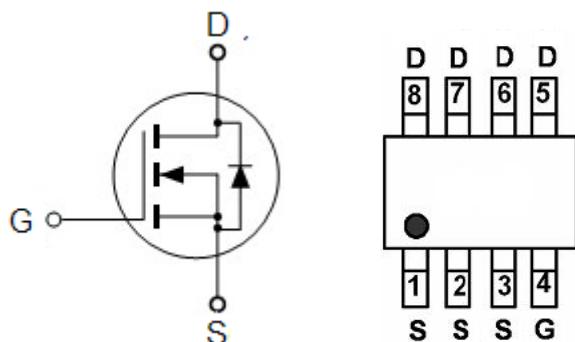
### General Description

**MEM2504** uses advanced trench technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety of applications.

### Features

- Low On-Resistance 60V/50A  $R_{DS(ON)} = 14m\Omega @ V_{GS} = 10V, I_D = 20A$
- High density cell design for ultra low  $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high  $E_{AS}$ .
- Special process technology for high ESD capability
- Surface mount package: SOP8

### Pin Configuration



### Maximum Ratings( $T_a=25^\circ C$ )

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		$V_{DSS}$	60	V
Drain Current	$T_A=25^\circ C$	50	16	A
	$T_A=100^\circ C$	35.4	8	
Pulsed Drain Current		$I_{DM}^1$	90	A
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Single Pulse Avalanche Energy		$E_{AS}^2$	245	mJ
Peak Diode Recovery		$dv/dt^3$	3.0	V/ns
Total Power Dissipation	$T_A=25^\circ C$	$P_d$	1.78	W
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	150, -55~150	°C
Maximum soldering temperature		$T_L$	300	°C

## Thermal Characteristics

Parameter	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>	70	°C/W

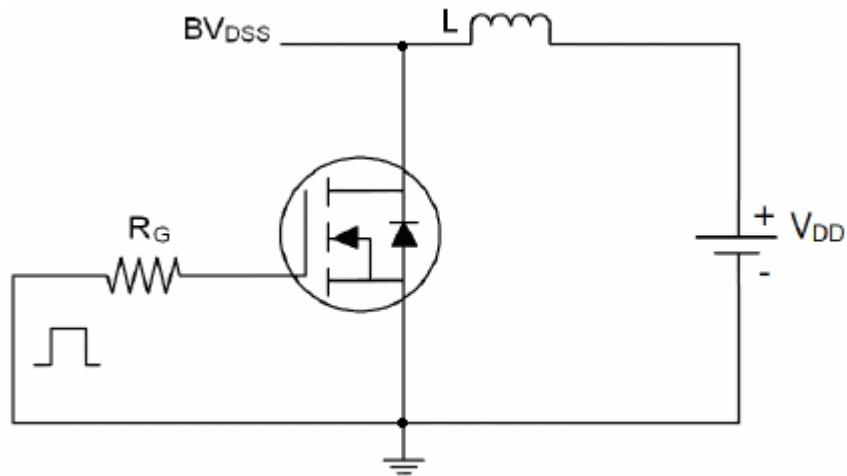
## Electrical Characteristics

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	-	-	V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.4	-	2.5	V
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =20V	-	-	100	nA
		V <sub>DS</sub> =0V, V <sub>GS</sub> =-20V	-	-	-100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V V <sub>GS</sub> =0V	-	-	1	μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	14	20	mΩ
Forward Trans conductance	g <sub>FS</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> = 20A	18	-	-	S
Drain-Source Diode Forward Continuous Current	I <sub>S</sub>	V <sub>GS</sub> =0V	-	-	50	A
Source-drain (diode forward) voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =8A	-	-	1.2	V
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz	-	2050	-	pF
Output Capacitance	C <sub>oss</sub>		-	158	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	120	-	
<b>Switching Characteristics</b>						
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 30 V, R <sub>G</sub> = 3Ω V <sub>GS</sub> = 10V, RL = 6.7Ω	-	7.4	-	ns
Rise Time	t <sub>r</sub>		-	5.1	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	28.2	-	
Fall-Time	t <sub>f</sub>		-	5.5	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DD</sub> = 30V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		50	-	nc
Gate-Source Charge	Q <sub>gs</sub>		-	6	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	15	-	

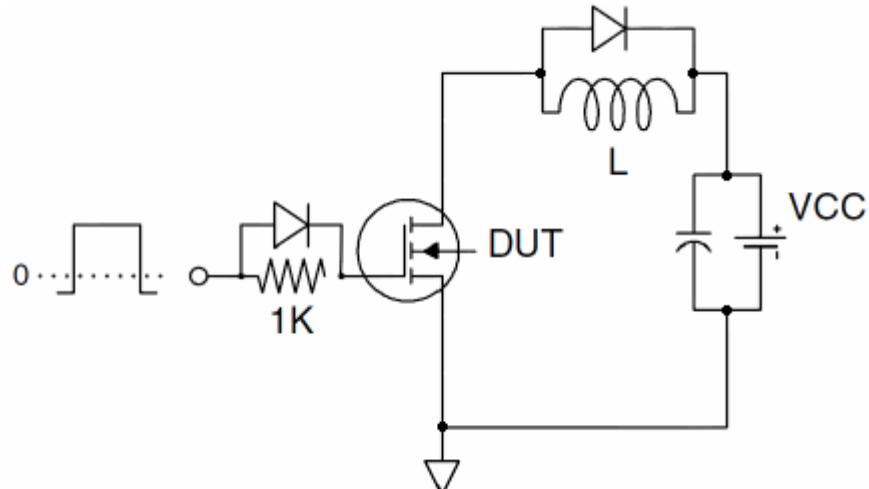
- Repetitive rating, pulse width limited by junction temperature.
- L=10.0mH, I<sub>D</sub>=8A, Start T<sub>J</sub>=25°C
- I<sub>SD</sub> =8A, di/dt≤100A/us, VDD≤BV<sub>DS</sub>, Start T<sub>J</sub>=25°C
- EAS condition: T<sub>J</sub>=25°C, VDD=30V, VG=10V, L=0.5mH, R<sub>g</sub>=25Ω

## Test Circuit

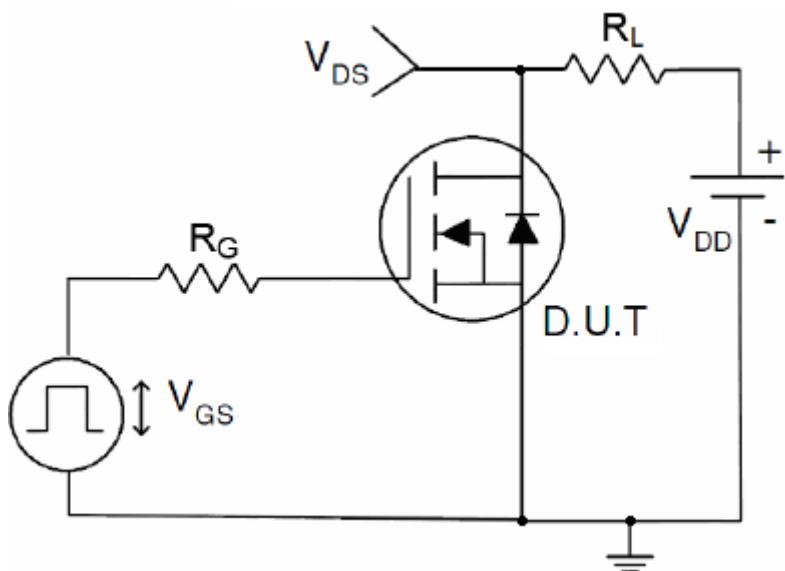
### 1. E<sub>AS</sub> test Circuit



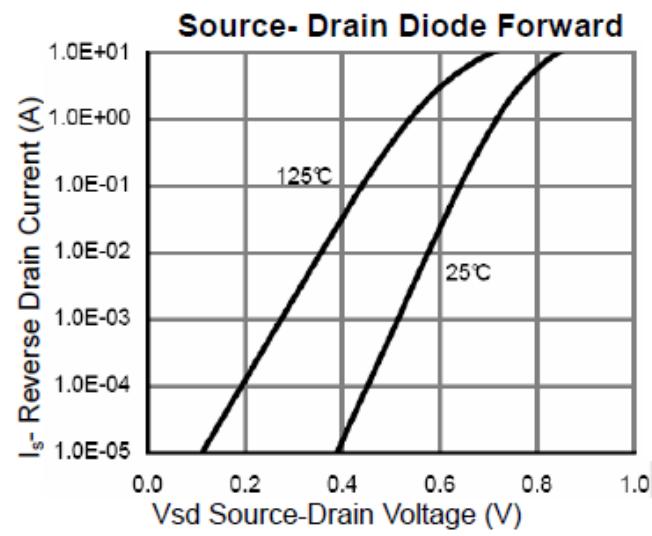
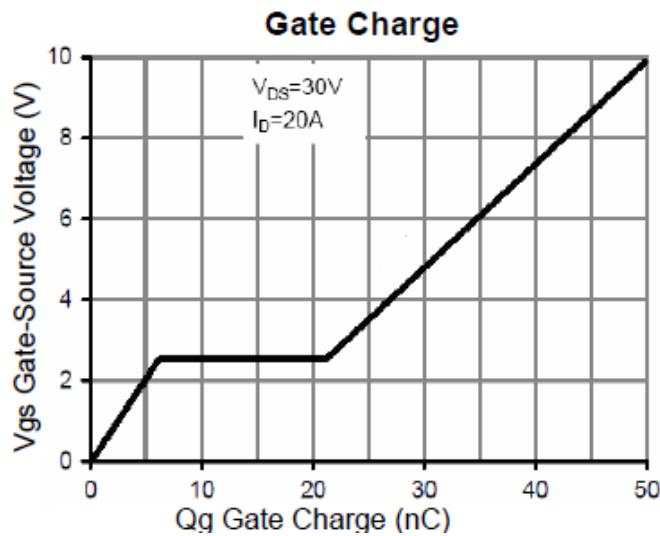
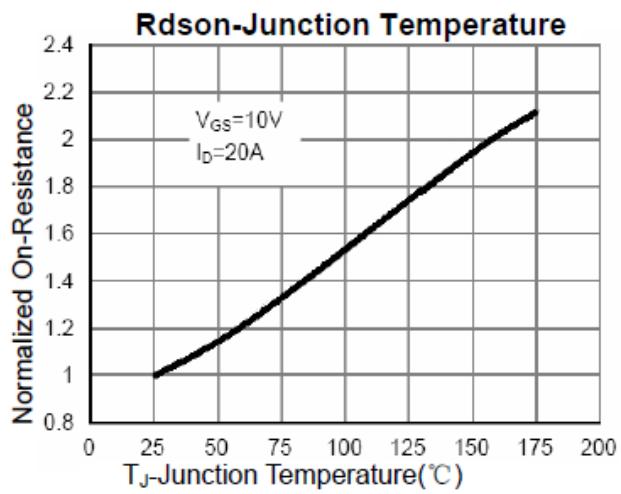
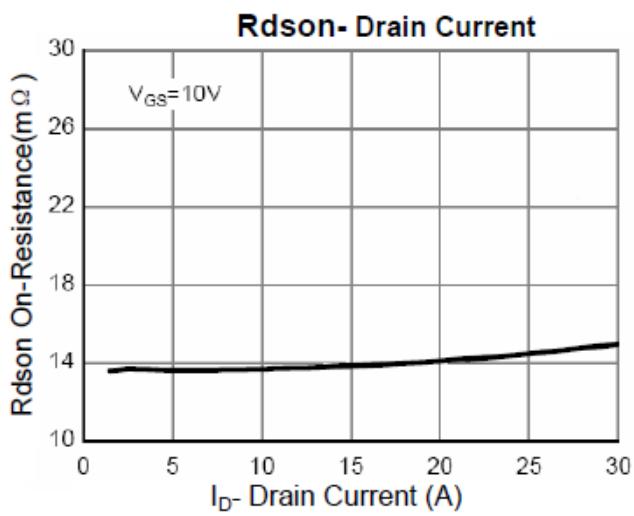
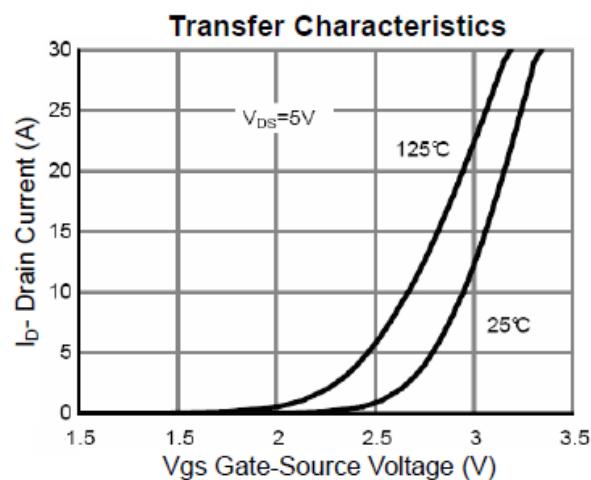
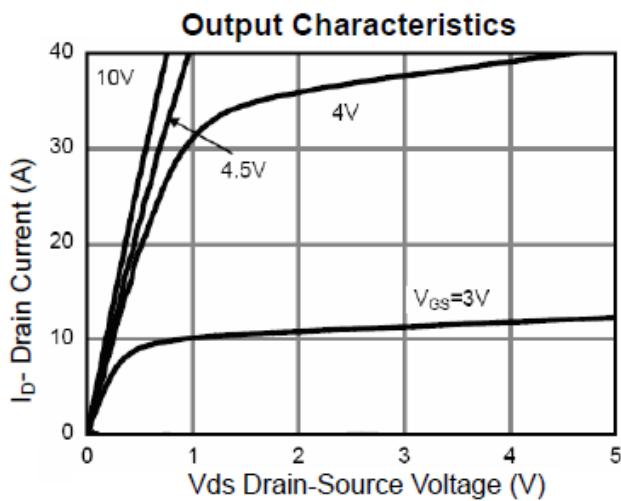
### 2. Gate charge test Circuit

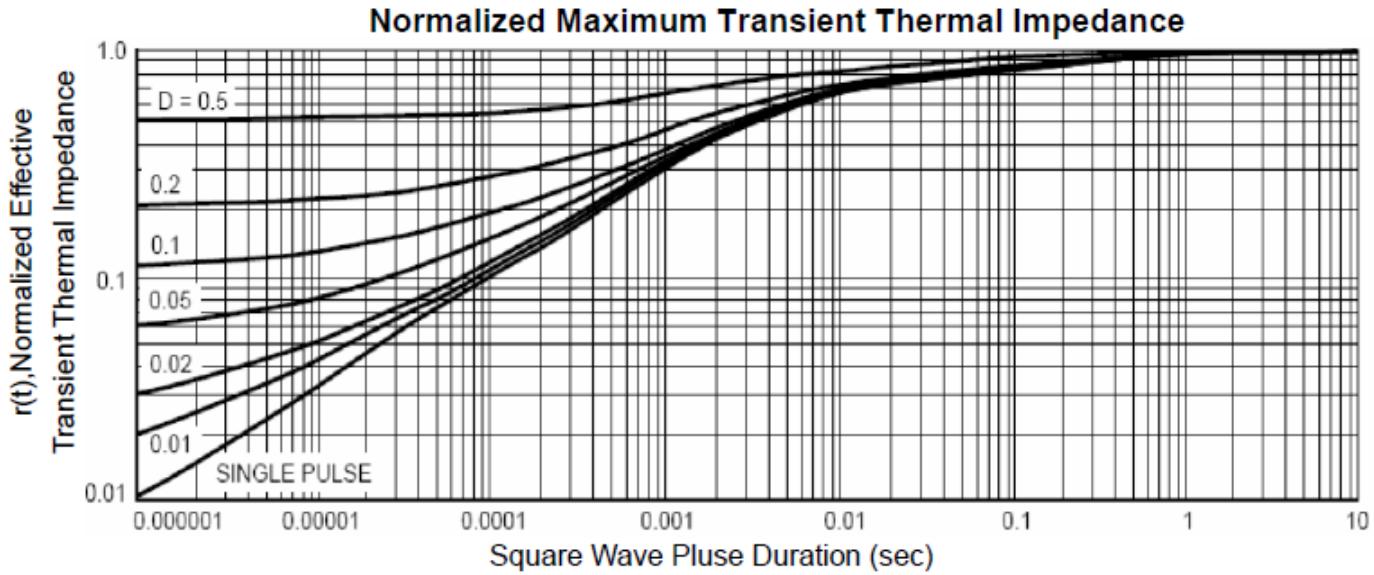
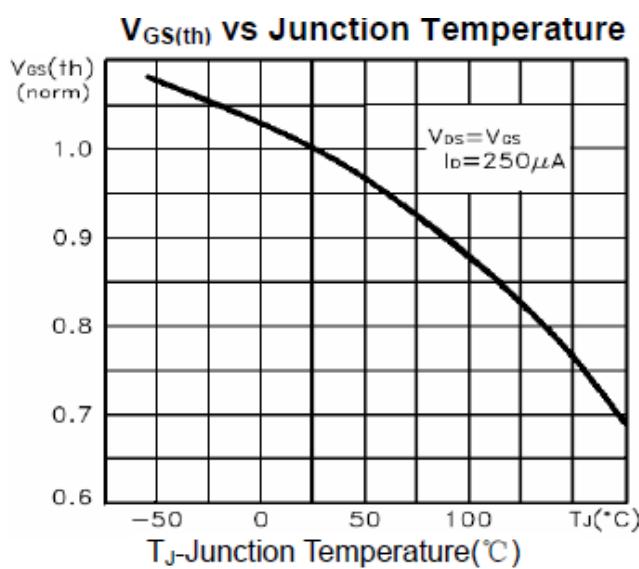
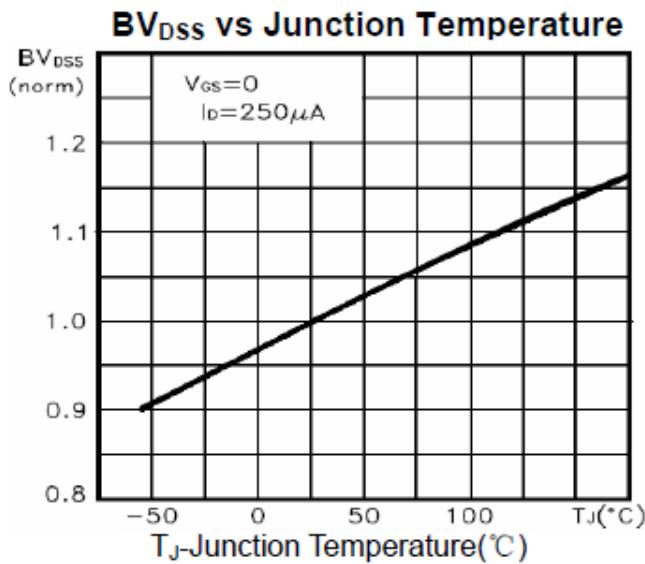
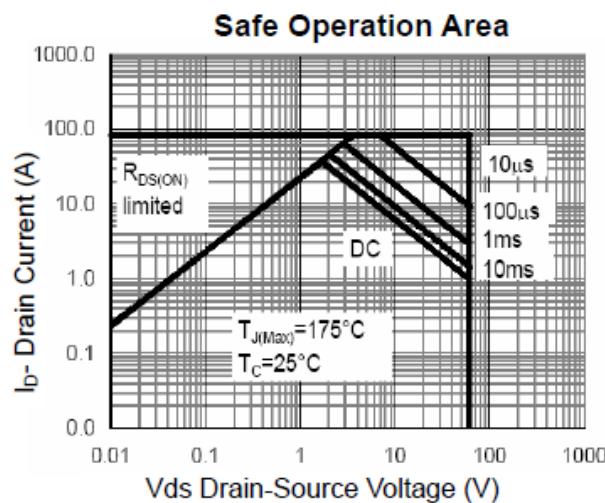
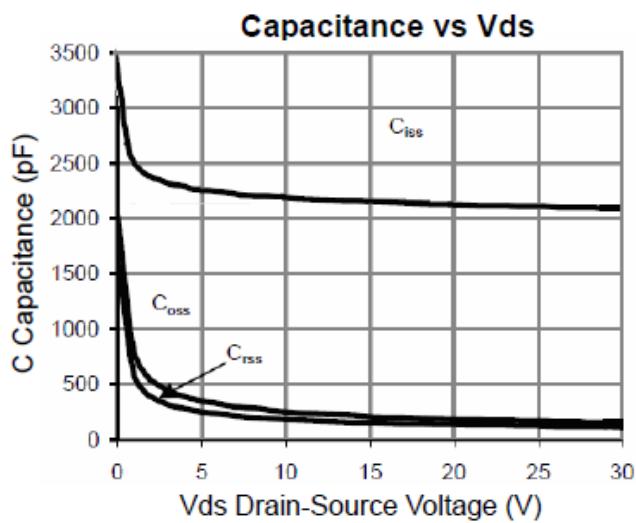


### 3. Switch Time Test Circuit



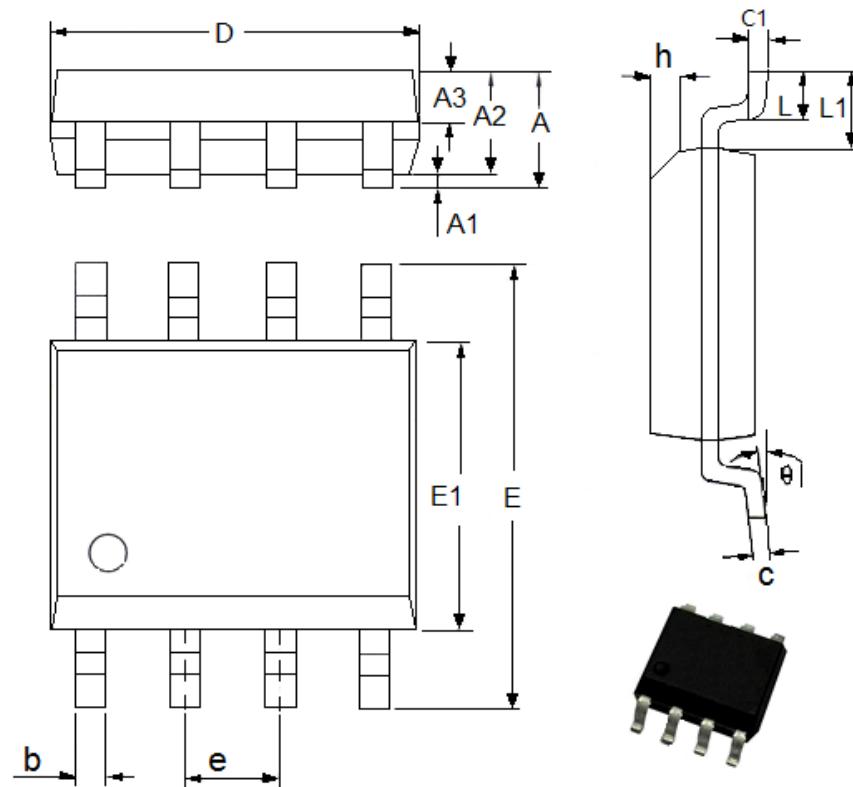
## Typical performance characteristics





## Package Information

- Package Type:SOP8



DIM	Millimeters		Inches	
	Min	Max	Min	Max
A	1.3	1.75	0.0512	0.0689
A1	0.05	0.25	0.002	0.0098
A2	1.25	1.65	0.0492	0.065
A3	0.5	0.7	0.0197	0.0276
b	0.33	0.51	0.013	0.0201
c	0.17	0.25	0.0067	0.0098
D	4.7	5.1	0.185	0.2008
E	5.8	6.2	0.2283	0.2441
E1	3.8	4	0.1496	0.1575
e	1.27(TYP)		0.05(TYP)	
h	0.25	0.5	0.0098	0.0197
L	0.4	1.27	0.0157	0.05
L1	1.04(TYP)		0.0409(TYP)	
θ	0	8°	0	8°
c1	0.25(TYP)		0.0098(TYP)	

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